



TJFW  
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PATENT  
Customer No. 22,852  
Attorney Docket No. 05225.0259

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

**TOMOHIRO SAITO et al.**

Application No.: 10/770,520

Filed: February 4, 2004

For: METHOD OF MANUFACTURING  
SEMICONDUCTOR DEVICES

)  
)  
)  
) Group Art Unit: 2825  
)  
) Examiner: Caridad Everhart  
)  
) Confirmation No. 1739

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**TRANSMITTAL LETTER**

Enclosed is a reply to the Office Action of August 6, 2004. The claims are calculated below:

	Claims Remaining After Amendment		Highest Number Previously Paid	Present Extra	Rate	Additional Fee
Total	22	-	20	2	x \$ 18	\$ 36
Indep.	0	-	4	0	x \$ 88	0
<input type="checkbox"/> First Presentation of Multiple Dep. Claim(s)					+\$300	0
Subtotal						\$ 36
Reduction by 1/2 if small entity						- 0
TOTAL						\$ 36

☒ A fee of \$36 to cover the cost of the additional claims added by this reply is enclosed. Please grant any extensions of time required to enter this response and charge any additional required fees to our deposit account 06-0916.

Dated: October 26, 2004

By: Richard V. Burgujian  
Robert E. Converse, Jr. #27,432  
Richard V. Burgujian  
Reg. No. 31,744



PATENT  
Customer No. 22,852  
Attorney Docket No. **05225.0259**

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**AMENDMENT**

In reply to the Office Action mailed August 6, 2004, the period for response to which extends through November 6, 2004 (a Sunday), please amend the above-identified application as follows:

**Amendments to the Claims** are reflected in the listing of claims in this paper beginning on page 2.

**Remarks** follow the amendment sections of this paper beginning on page 10.